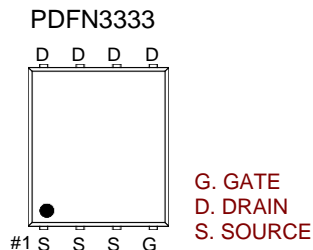


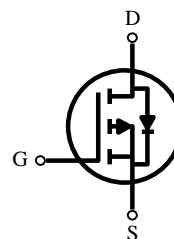
## P -Channel High Density Trench MOSFET

### FEATURES

- Super high dense cell trench design for low  $R_{DS(on)}$ .
- Rugged and reliable.
- Surface Mount package.



PRODUCT SUMMARY		
$V_{(BR)DSS}$	$R_{DS(on)}$ (m $\Omega$ ) Max	$I_D$
-40V	13 @ $V_{GS} = -10V$	-40A
	19 @ $V_{GS} = -4.5V$	



### ABSOLUTE MAXIMUM RATINGS (TA = 25 °C unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	$V_{DS}$	-40	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Drain Current-Continuous	$I_D$	TC=25°C	-40
		TC=100°C	-25
Pulsed Drain Current (Note 1)	$I_{DM}$	-120	A
Avalanche Current	$I_{AS}$	-54	
Single Pulse Avalanche Energy	L = 0.1mH $E_{AS}$	146	mJ
Maximum Power Dissipation (Note 1)	$P_D$	TC=25°C	-54
		TC=100°C	19.8
Operating Junction and Storage Temperature Range	$T_J, T_{STG}$	- 55 to 150	°C

### TYPICAL THERMAL CHARACTERISTICS (Note 1)

Thermal Resistance, Junction-to-Case	$R_{thJC}$	4	°C/W
Thermal Resistance Junction-Ambient	$R_{thJA}$	62	°C/W

Note :

1. Pulse width limited by maximum junction temperature.

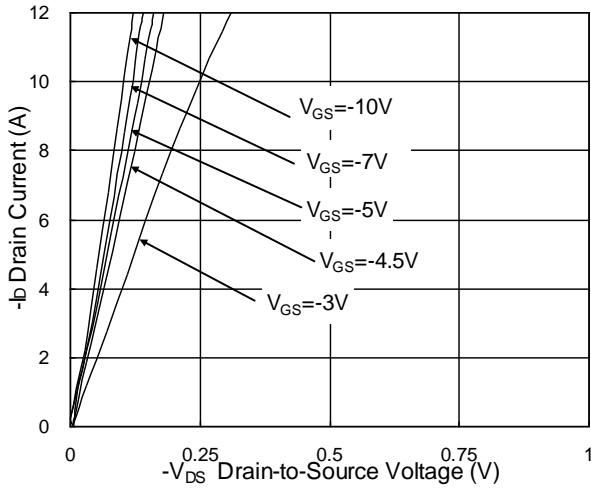
**ELECTRICAL CHARACTERISTICS (TA = 25 °C unless otherwise noted)**

Parameter	Symbol	Condition	Min	Typ	Max	Unit
<b>OFF CHARACTERISTICS</b>						
Drain-Source Breakdown Voltage	$BV_{DSS}$	$V_{GS} = 0V, I_D = -250\mu A$	-40			V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = -32V, V_{GS} = 0V, T_j = 25^\circ C$			-1	uA
		$V_{DS} = -32V, V_{GS} = 0V, T_j = 100^\circ C$			-10	
Gate-Body Leakage	$I_{GSS}$	$V_{GS} = \pm 20V, V_{DS} = 0V$			$\pm 100$	nA
<b>ON CHARACTERISTICS (Note 2)</b>						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	-1	-1.6	-2.5	V
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = -10V, I_D = -20A$		11	13	m $\Omega$
		$V_{GS} = -4.5V, I_D = -12A$		15.5	19	m $\Omega$
Forward Transconductance	gfs	$V_{DS} = -5V, I_D = -10A$		23		S
<b>DYNAMIC CHARACTERISTICS</b>						
Input Capacitance	$C_{ISS}$	$V_{DS} = -15V, V_{GS} = 0V$ $f = 1.0MHz$		3480		pF
Output Capacitance	$C_{OSS}$			321		pF
Reverse Transfer Capacitance	$C_{RSS}$			217		pF
Gate Resisance	$R_g$	$V_{DS} = 0V, V_{GS} = 0V, f = 1.0MHz$		7		$\Omega$
<b>SWITCHING CHARACTERISTICS (Note 3)</b>						
Turn-On Delay Time	$td_{(ON)}$	$V_{DD} = -15V, I_D = -6A, V_{GS} = -10V$ $R_{GS} = 3.3\Omega$		40		nS
Rise Time	tr			35.2		nS
Turn-Off Delay Time	$td_{(OFF)}$			100		nS
Fall Time	tf			9.6		nS
Total Gate Charge (10V)	Qg	$V_{DS} = -20V, I_D = -12A$ $V_{GS} = -4.5V$		44		nC
Total Gate Charge (4.5V)	Qg			28		nC
Gate-Source Charge	Qgs			7.7		nC
Gate-Drain Charge	Qgd			7.5		nC
<b>DRAIN-SOURCE DIODE CHARACTERISTICS</b>						
Continuous Current	$I_S$			-40		A
Diode Forward Voltage (Note 2)	$V_{SD}$	$V_{GS} = 0V, I_S = I_F$		-0.7	-1.1	V

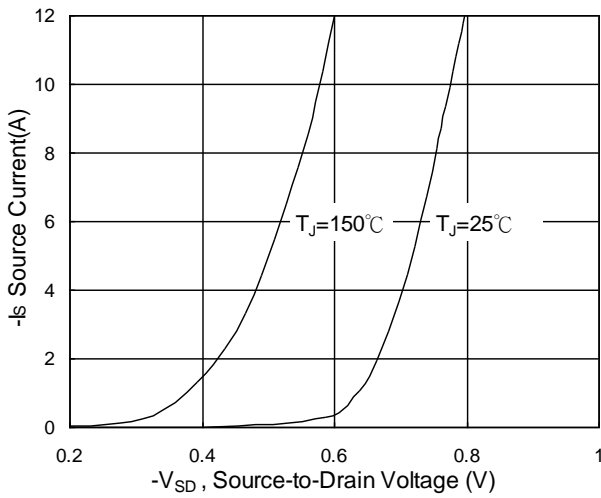
Note :

2. Pulse Test Pulse width  $\leq 300\mu sec$ , Duty Cycle  $\leq 2\%$
3. Independent of operating production testing.

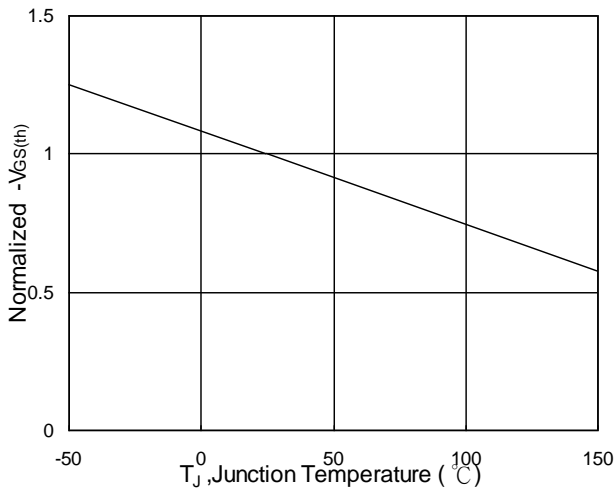
**Typical Characteristics**



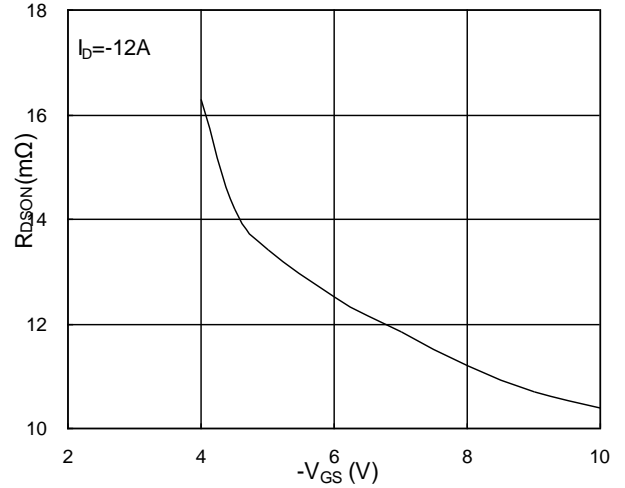
**Typical Output Characteristics**



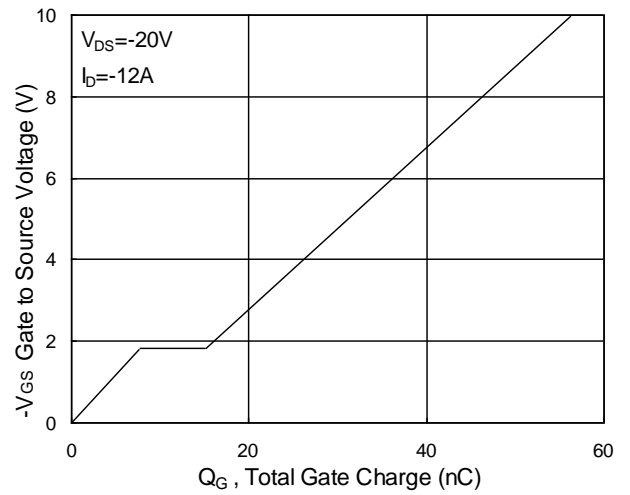
**Source Drain Forward Characteristics**



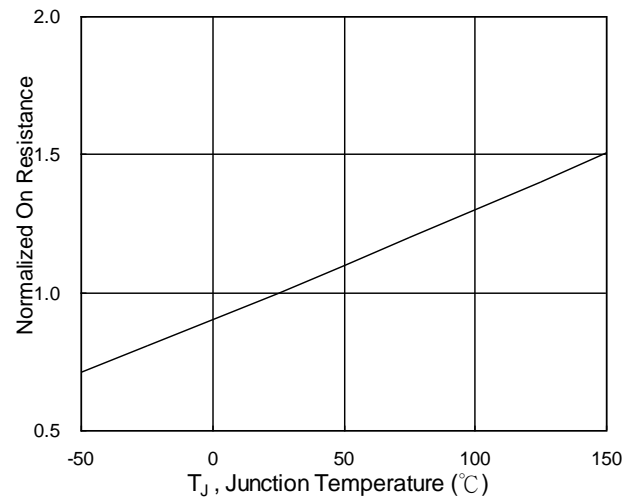
**Normalized V<sub>GS(th)</sub> vs T<sub>J</sub>**



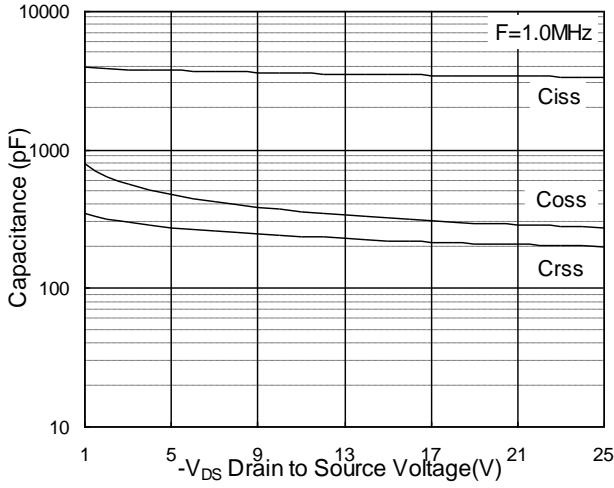
**On-Resistance vs G-S Voltage**



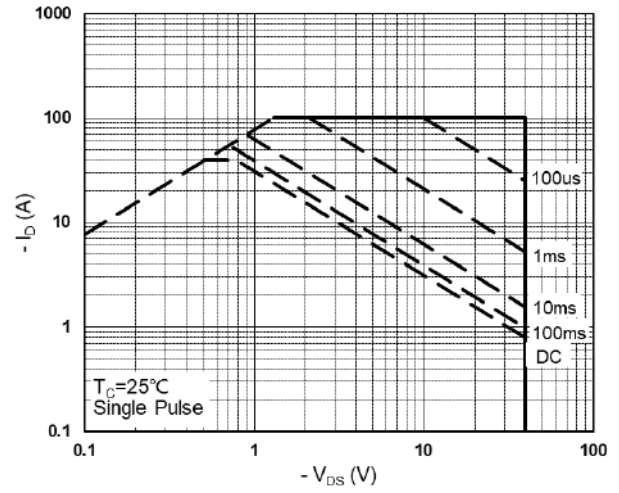
**Gate-Charge Characteristics**



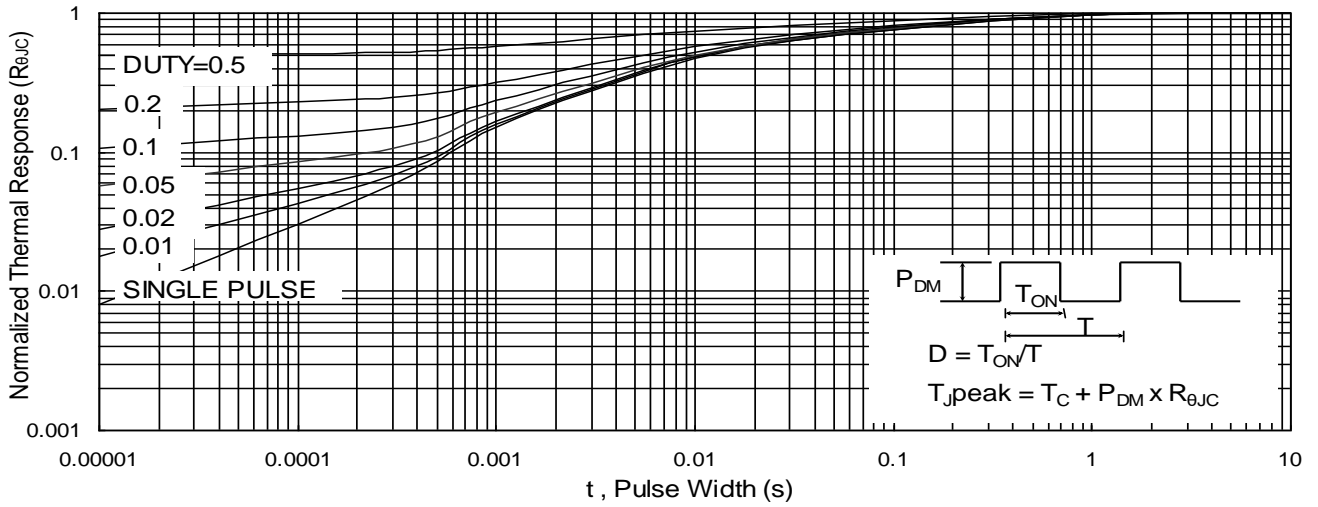
**Normalized R<sub>DS(on)</sub> vs T<sub>J</sub>**



**Capacitance**



**Safe Operating Area**



**Normalized Maximum Transient Thermal Impedance**